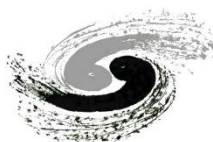




# Sensor and electronics design for the Vertex Detector

Ying Zhang

(On behalf of the CEPC vertex detector group)



中國科學院高能物理研究所  
*Institute of High Energy Physics*  
*Chinese Academy of Sciences*

# Content

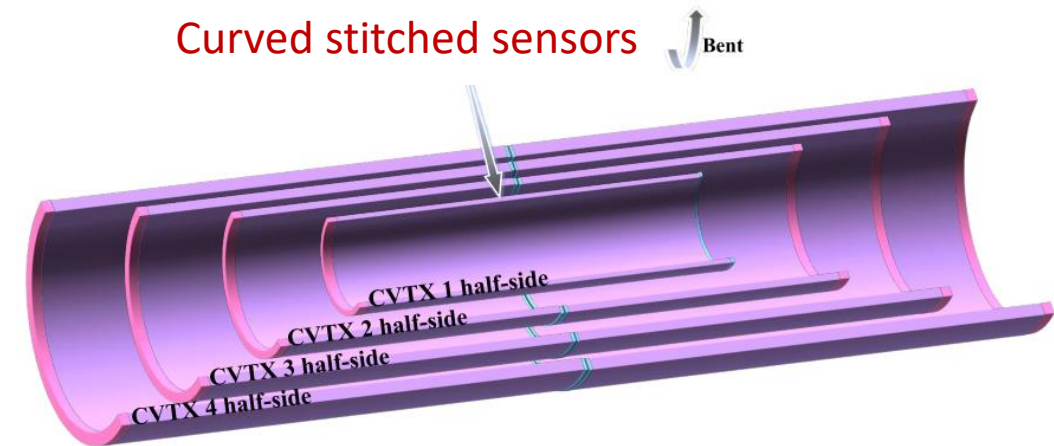
- **CEPC Vertex detector requirements**
- **R&D efforts and results**
- **Stitched sensor prototype design**
- **Readout electronics**
- **Summary**

# Vertex Requirement

- Inner most layer (b-layer) need to be positioned as close to beam pipe as possible
  - Challenges: Radius (11.1 mm) is smaller compared with ALICE ITS3 (18 mm)  
Requiring wafer-scale stitched Monolithic Active Pixel Sensors (MAPSs)

**Table 4.2:** Vertex Detector Design Parameters

Parameter	Design
Spatial Resolution	<u><math>\sim 5 \mu\text{m}</math></u>
Detector material budget	<u><math>\sim 0.8\% X_0</math></u>
First layer radius	11.1 mm
Power Consumption	<u><math>&lt; 40 \text{ mW/cm}^2</math></u> (air cooling requirement)
Time stamp precision	100 ns
Fluence	$\sim 2 \times 10^{14} \text{ Neq/cm}^2$ (for first 10 years)
Operation Temperature	$\sim 5^\circ\text{C}$ to $30^\circ\text{C}$
Readout Electronics	Fast, low-noise, low-power
Mechanical Support	Ultralight structures
Angular Coverage	$ \cos \theta  < 0.99$



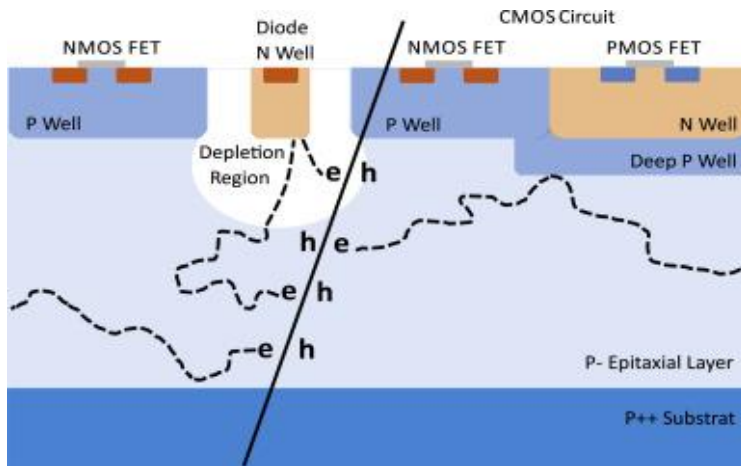
First four semi-cylinder layers for CEPC VTX

# Technology for CEPC Reference TDR

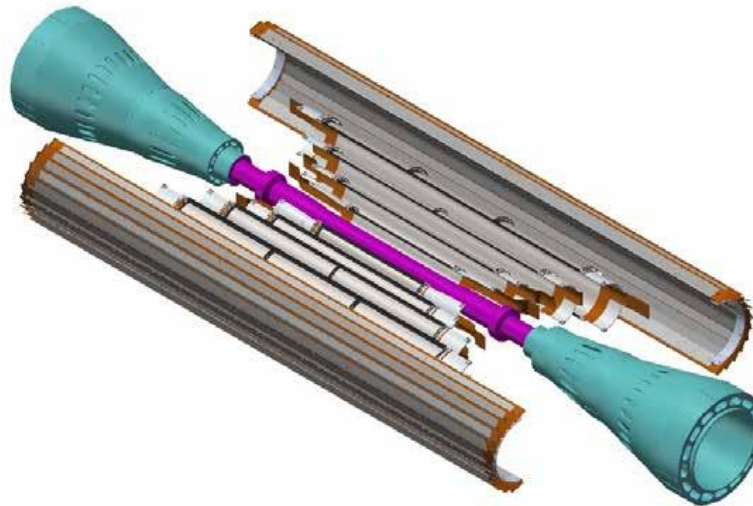
## ■ Vertex detector Technology selection

- Baseline: based on curved CMOS MAPS (Inspired by ALICE ITS3 design [1])
  - Advantage: 2~3 times smaller material budget compared to alternative (ladder)
- Alternative: ladder design based on CMOS MAPS

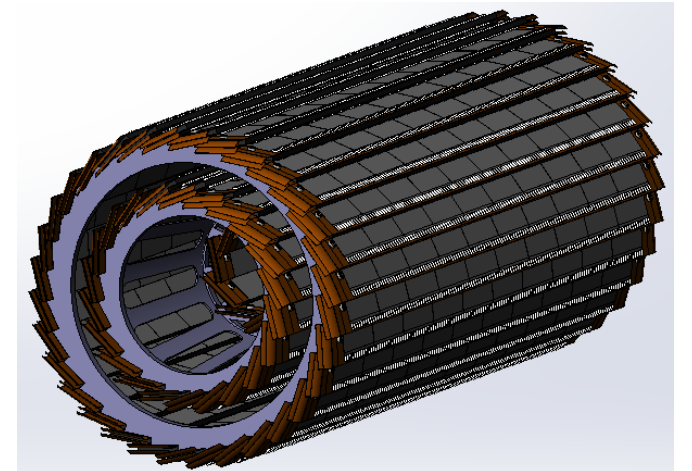
CMOS Monolithic Active Pixel Sensor



Baseline: curved MAPS



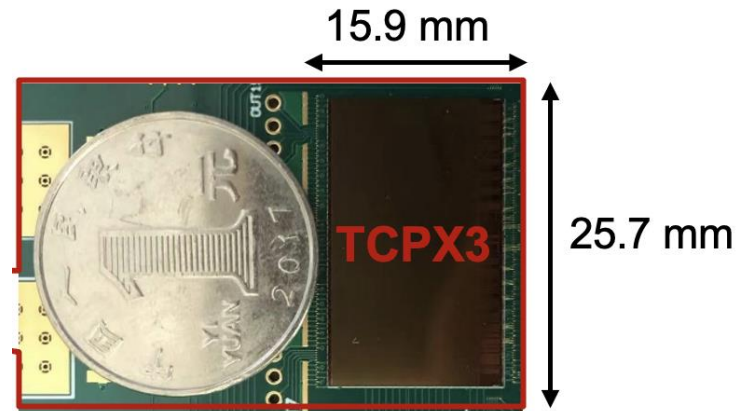
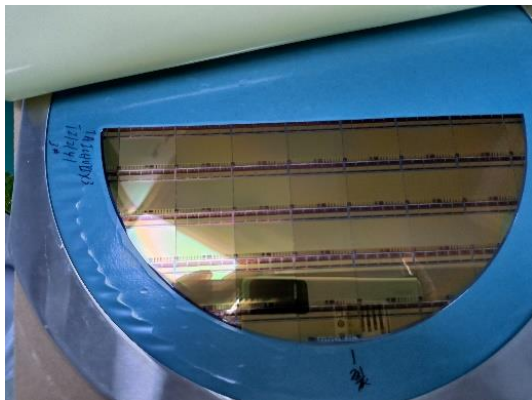
Alternative: ladder based MAPS



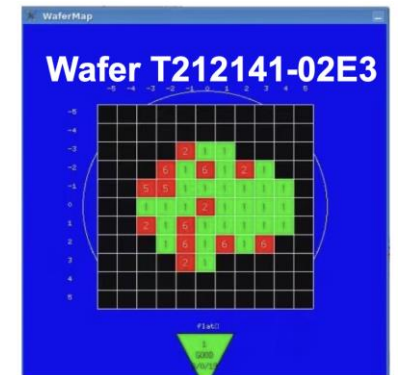
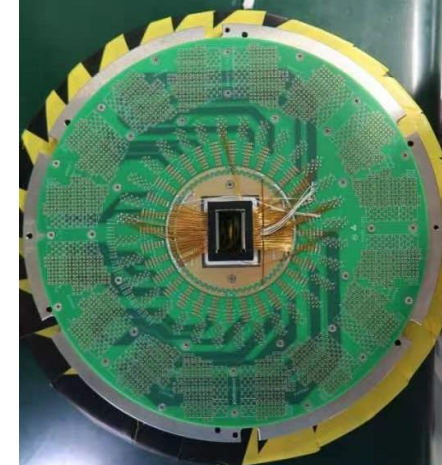


# R&D efforts: Full-size pixel sensor chip

- Full reticle-size CMOS MAPS developed, 1<sup>st</sup> engineering run
  - 1024×512 pixel array, Chip Size: 15.9 mm×25.7 mm
  - 25 μm×25 μm pixel size with high spatial resolution < 5 μm (@ detection eff. > 99%)
  - Process: 180 nm CIS process
  - Fast data-driven readout (50 ns/pixel) to cope with all operation modes in CDR
    - Dead time < 500 ns, Max. hit rate 36 MHz/cm<sup>2</sup>



TaichuPix-3 chip vs. coin

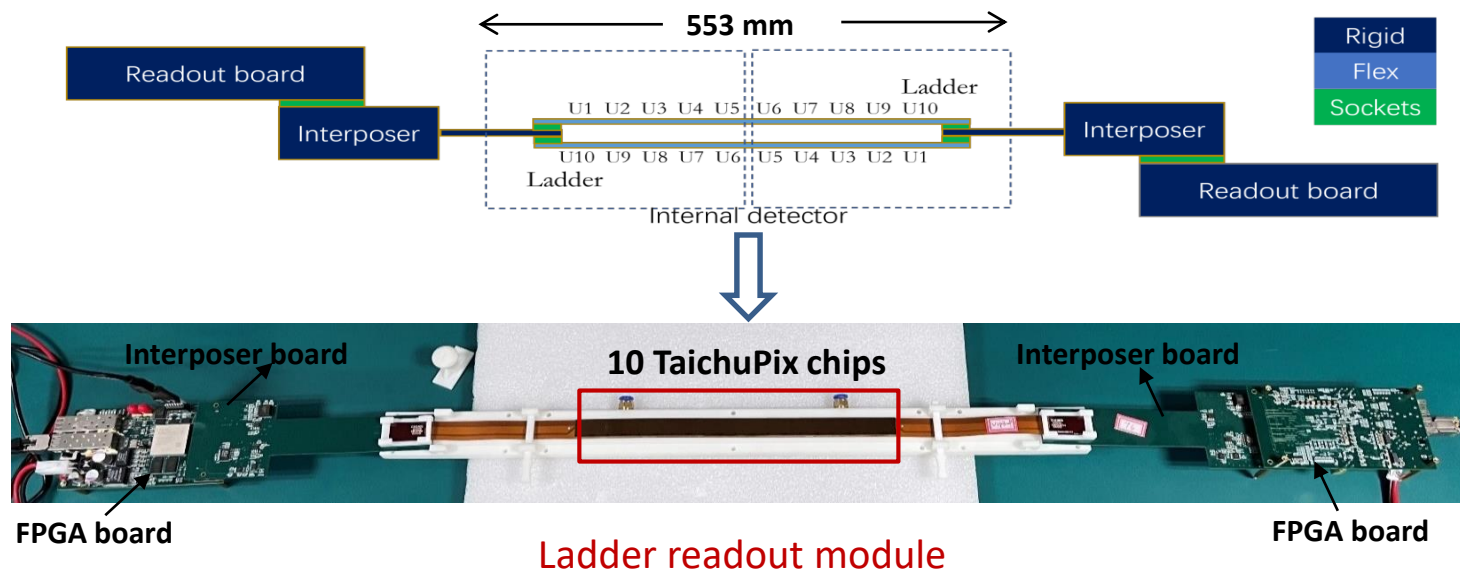


An example of wafer test result

	Status	CEPC Final goal
CMOS chip technology	Full-size chip with 180 nm CIS	65 nm CIS

# R&D effort: Ladder readout design

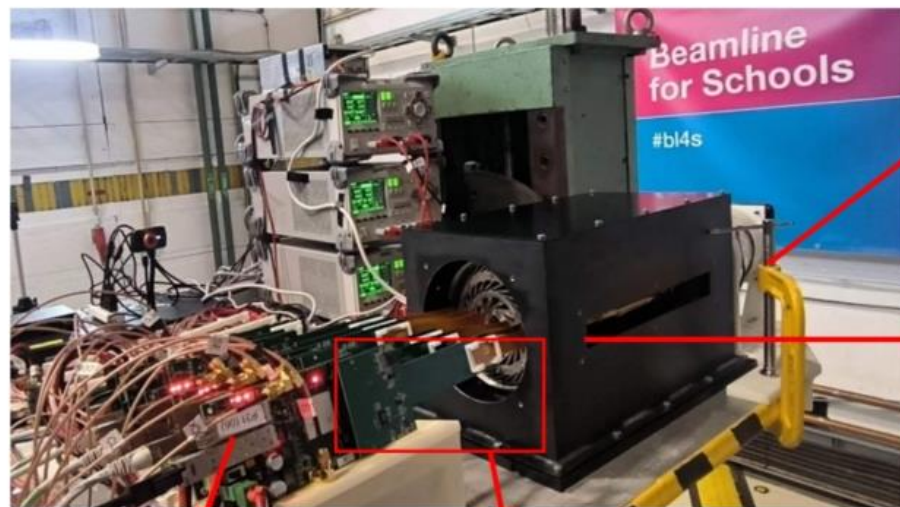
- Detector module (ladder) = 10 sensors (on oneside) + support structure + readout board
  - Sensors are wire bonded to the flexible PCB, supported by a carbon fiber support
  - Signal, clock, control, power, ground will be handled by readout board through flexible PCB
- Functionality of a full ladder readout was verified
  - Read out from both ends, with careful design on power placement and low noise



# R&D effort: Vertex detector prototype

## ■ 6 double-sided layers assembled on detector prototype

- 12 flex boards with two TaichuPix-3 chips bonded on each flex
- Readout boards on one side of the detector
- Best spatial resolution  $4.97 \mu\text{m}$  @ detection efficiency  $> 99\%$



FPGA board

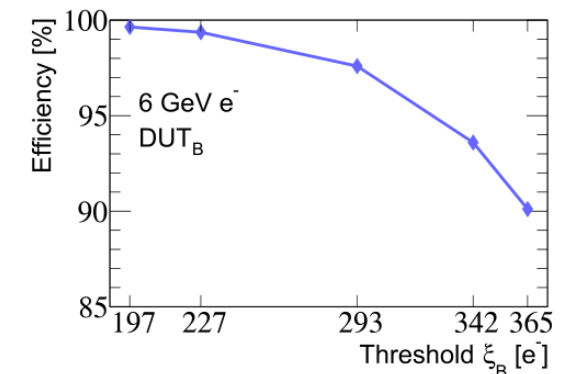
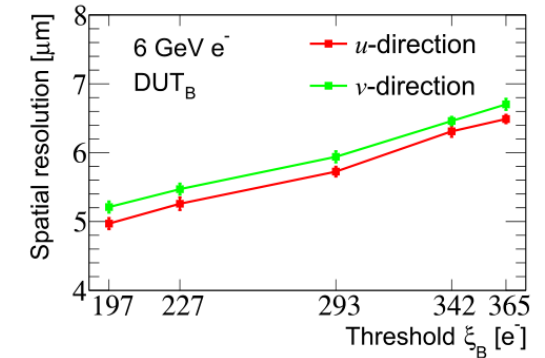
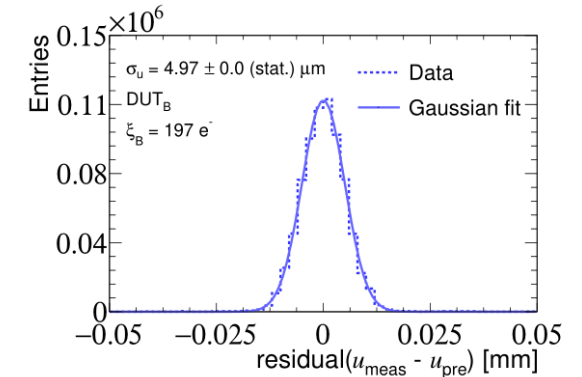
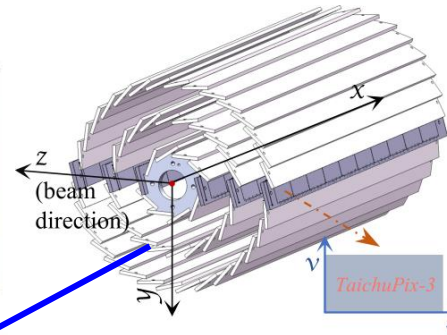
Interposer board



Air cooling fan

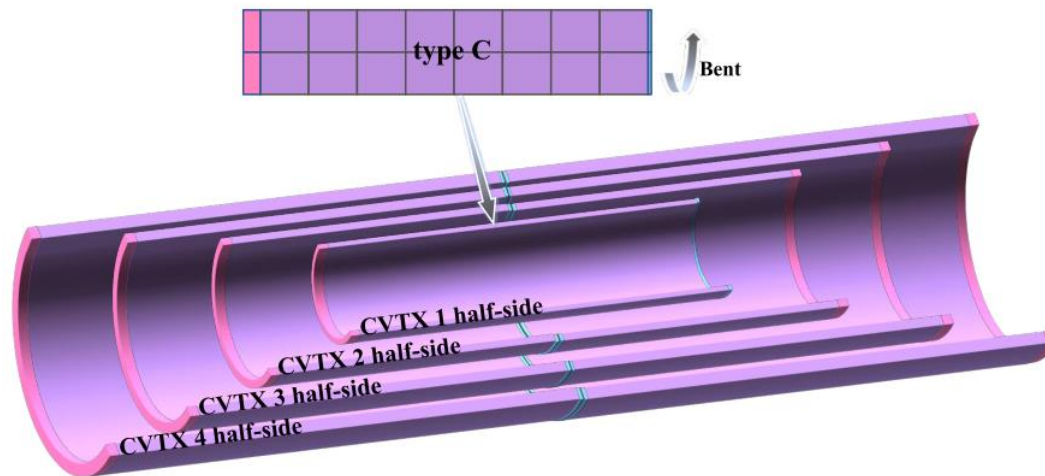


First vertex detector prototype

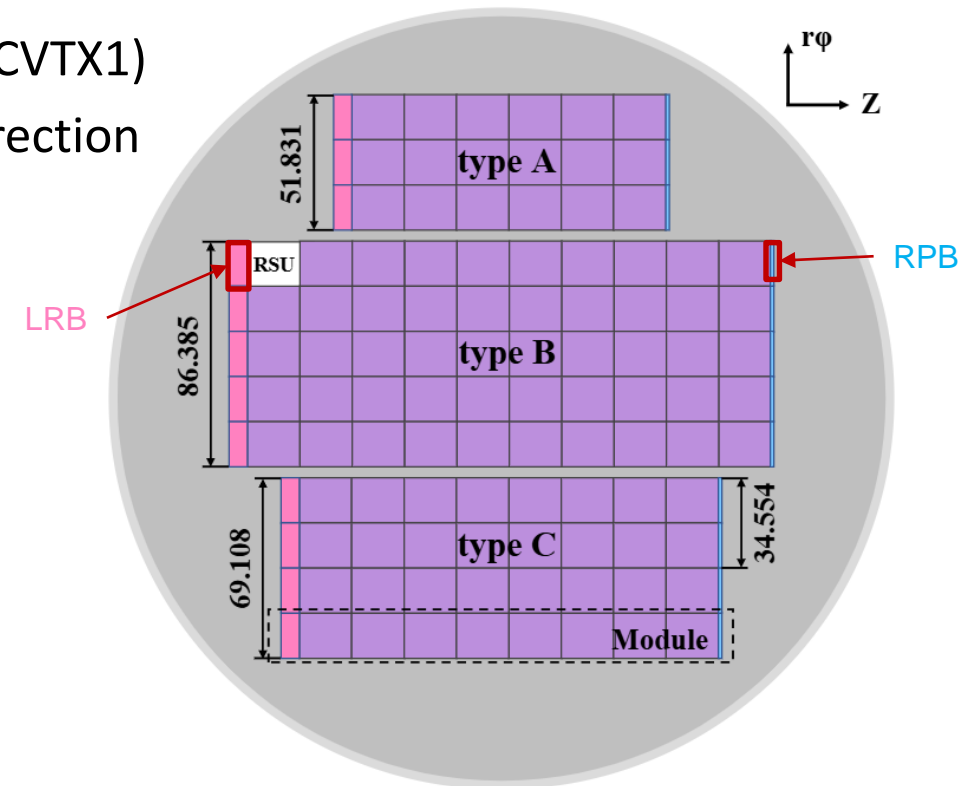


# Stitched sensor prototype design

- Requiring wafer-scale bent pixel sensors for inner layers
  - Three types stitched sensors with different sizes on a wafer
    - Sharing same components (RUS, LRB, RPB)
    - One Type C sensor forms a semi-cylindrical for layer1 (CVTX1)
    - Two Type A/Type C/Type B sensors oriented along z-direction to form halves for Layer2/Layer3/Layer4



First four semi-cylinder layers for CEPC VTX

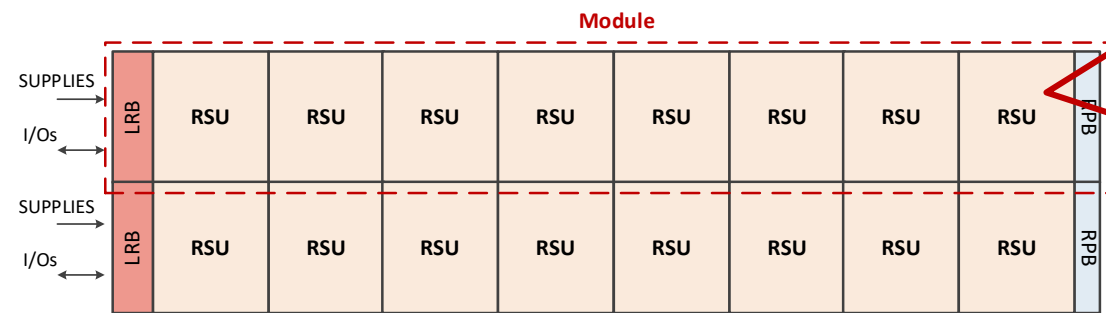
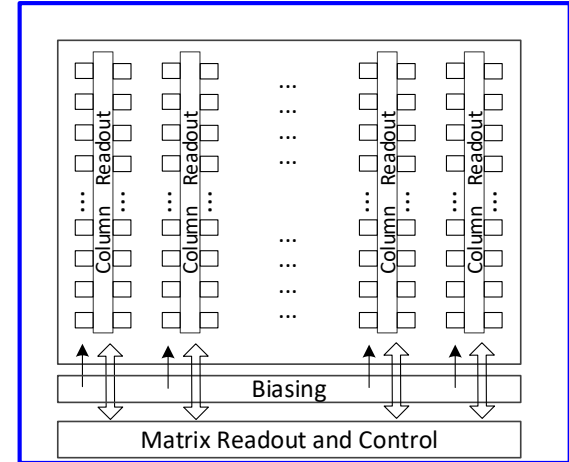


Stitching plan for a 300 mm wafer

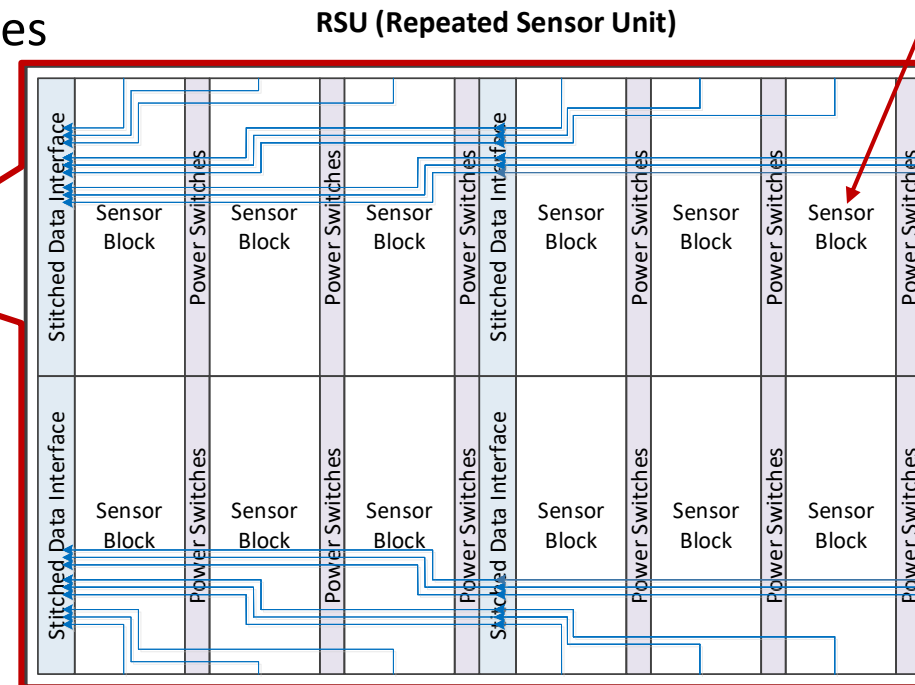


# Stitched sensor prototype design

- Each stitched prototype consists of multiple RSUs (Repeated Sensor Unit), 1 LRB (Left-end Readout Block) and 1 RPB (Right-end Power Block).
  - An RSU is composed of multiple independent Sensor Blocks, each transmits low-speed serialized data to the left edge of chip.
  - LRB acts as data collector, high-speed data interface and power supply with external.
  - RPB contains solely power transmission buses



Schematic floorplan of the sensor for layer1



**Sensor Block**  
(design derived from TaichuPix3)

# Design of the first stitched chip

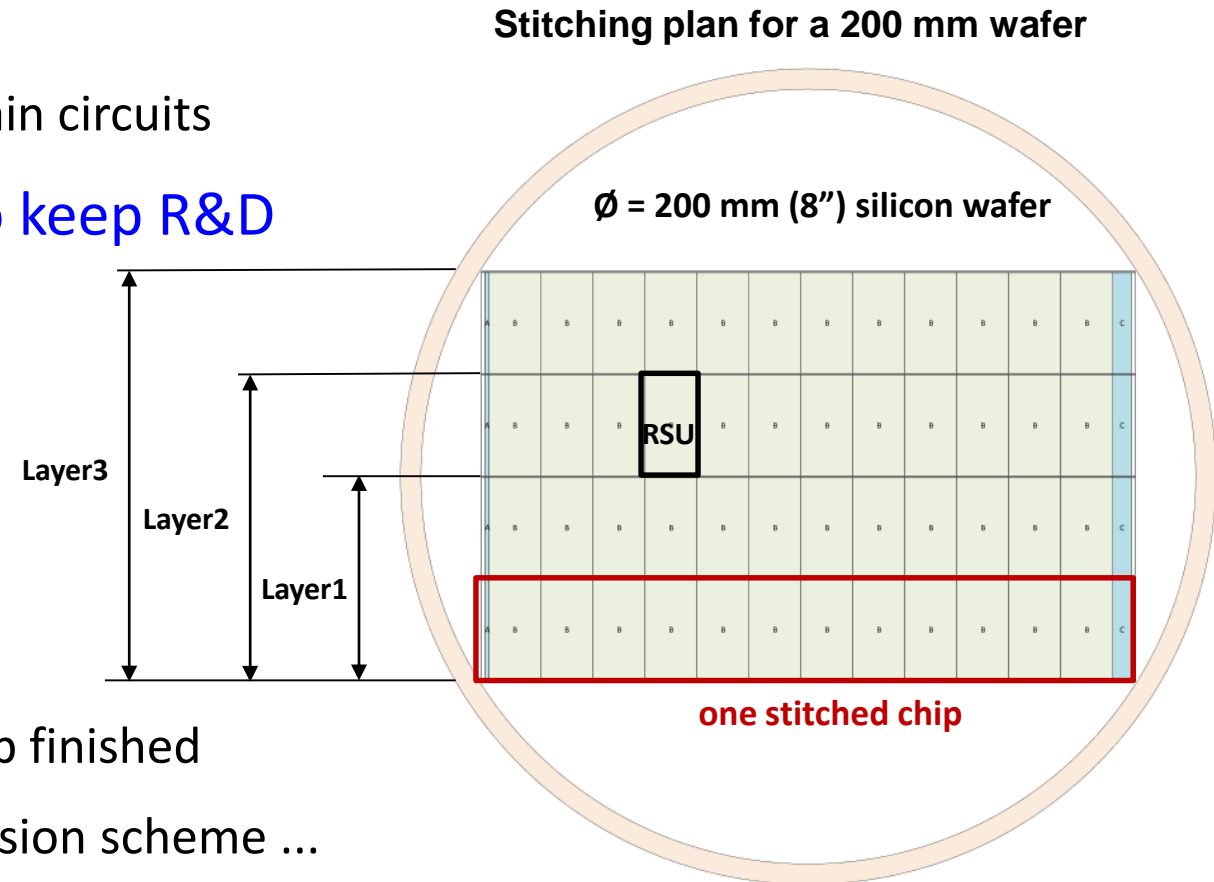
## ■ Main goals:

- Feasibility validation of the stitching technology
- Architecture and functionality validation of the main circuits

## ■ Design based on previous R&D prototypes, to keep R&D risks and costs within reasonable bounds.

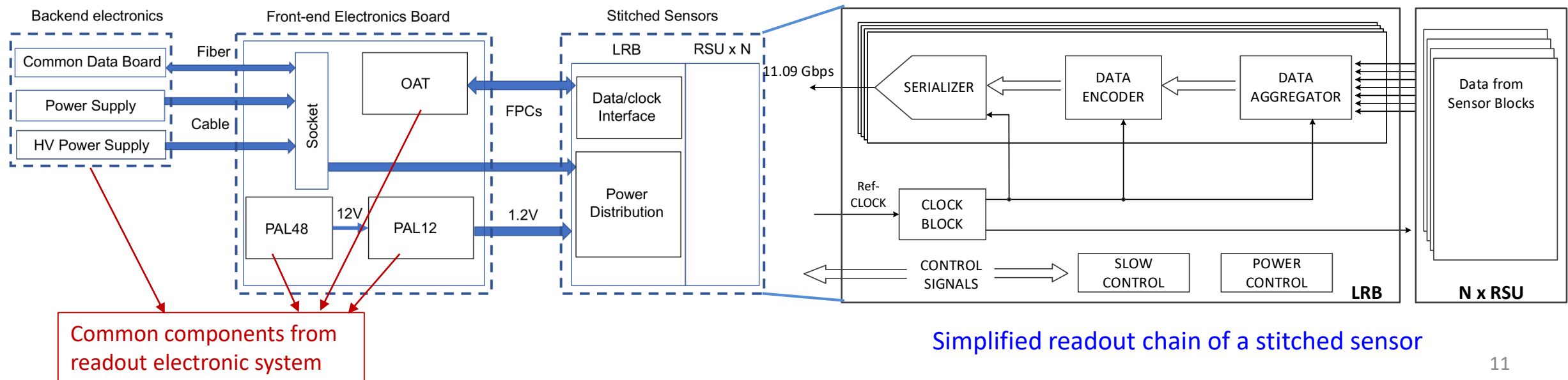
## ■ Design status

- Preliminary design of stitching floorplan done
  - Four stitched chips per wafer
- Preliminary architecture design of the stitched chip finished
  - Chip size, specific RSU floorplan, data transmission scheme ...
- Detailed circuit design ongoing



# Readout electronics

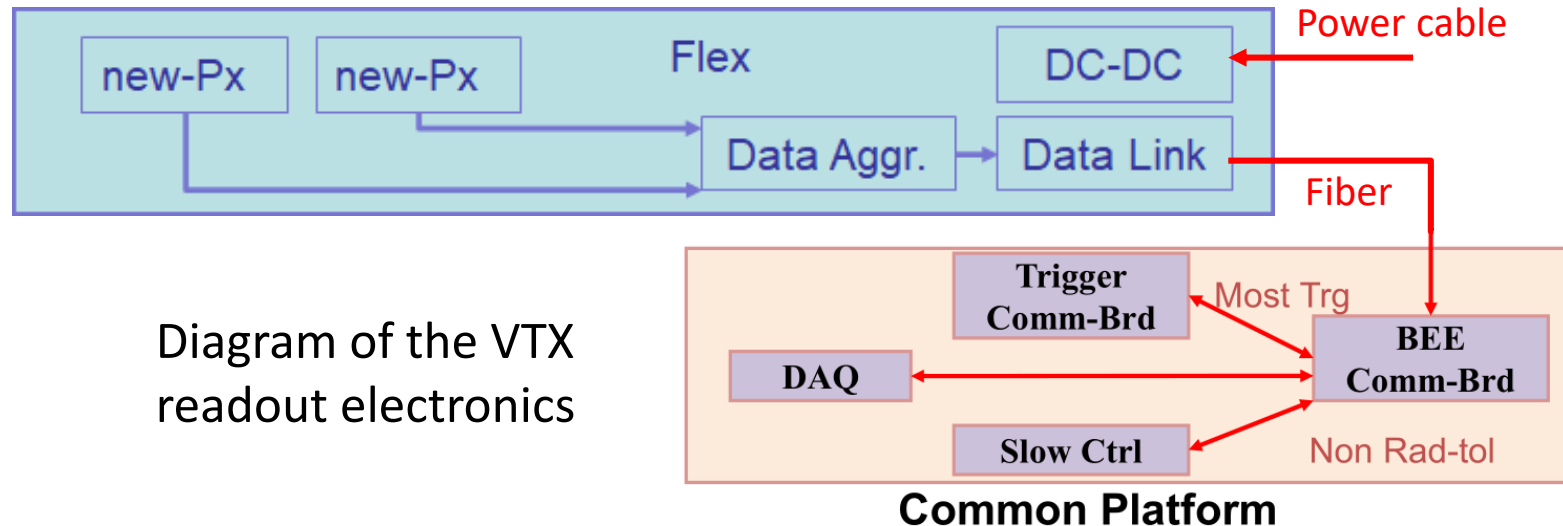
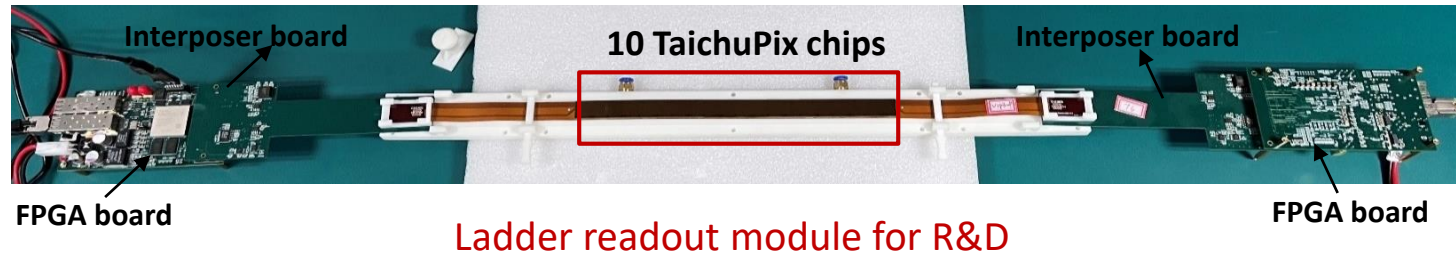
- **Stitched sensors wire-bonded on FPCs to connect to Front-end Electronics Board (FEE)**
  - LRB of stitched sensors aggregates data of RSUs, distributes clock and control signals, and handles local power distribution
- **FEE boards include optical transceivers and power regulators**
  - OAT (Optical Array Transceiver) converts electrical signals into optical signals and transmits them over fibers to Back-End Electronics (BEE)
  - Power management: two-stage DC-DC conversion scheme (two Power-at-Load (PAL) modules)



Simplified readout chain of a stitched sensor

# Readout electronics

- Outer layer (L5-L6): flexible PCB (also used in alternative layout)
  - Preliminary ladder readout module verified in previous R&D
  - Customized rad-tolerant ASICs will be used for data link and DC-DC converter



Background data rate and cabling on data

	Higgs	Low-Lumi Z
Background hit rate (MHz/cm <sup>2</sup> )	6.4	15
Data rate/Link (Gbps)	20	47
Fiber channels to BEE		96
BEEs		6
Crates		1

Talk on BEE: 5:10 PM, 8<sup>th</sup> Nov., Jun Hu



# Summary

- CEPC vertex detector requires wafer-scale monolithic pixel sensors for the inner four layers
  - First stitched chip based on 180 nm process under designing
    - Feasibility validation of the stitching technology
    - Architecture and functionality validation of the main circuits
  - Next generation stitched chip expected to transition to 65/55 nm
- Customized front-end electronics (FEE) for VTX
  - For Layer1-4, FEE boards contain optical transceivers and power regulators
  - For Layer5-6, ladder readout will be built based on the previous R&D
- Back-end electronics (BEE) of VTX based on the common platform
  - Common platform for all sub-detector system



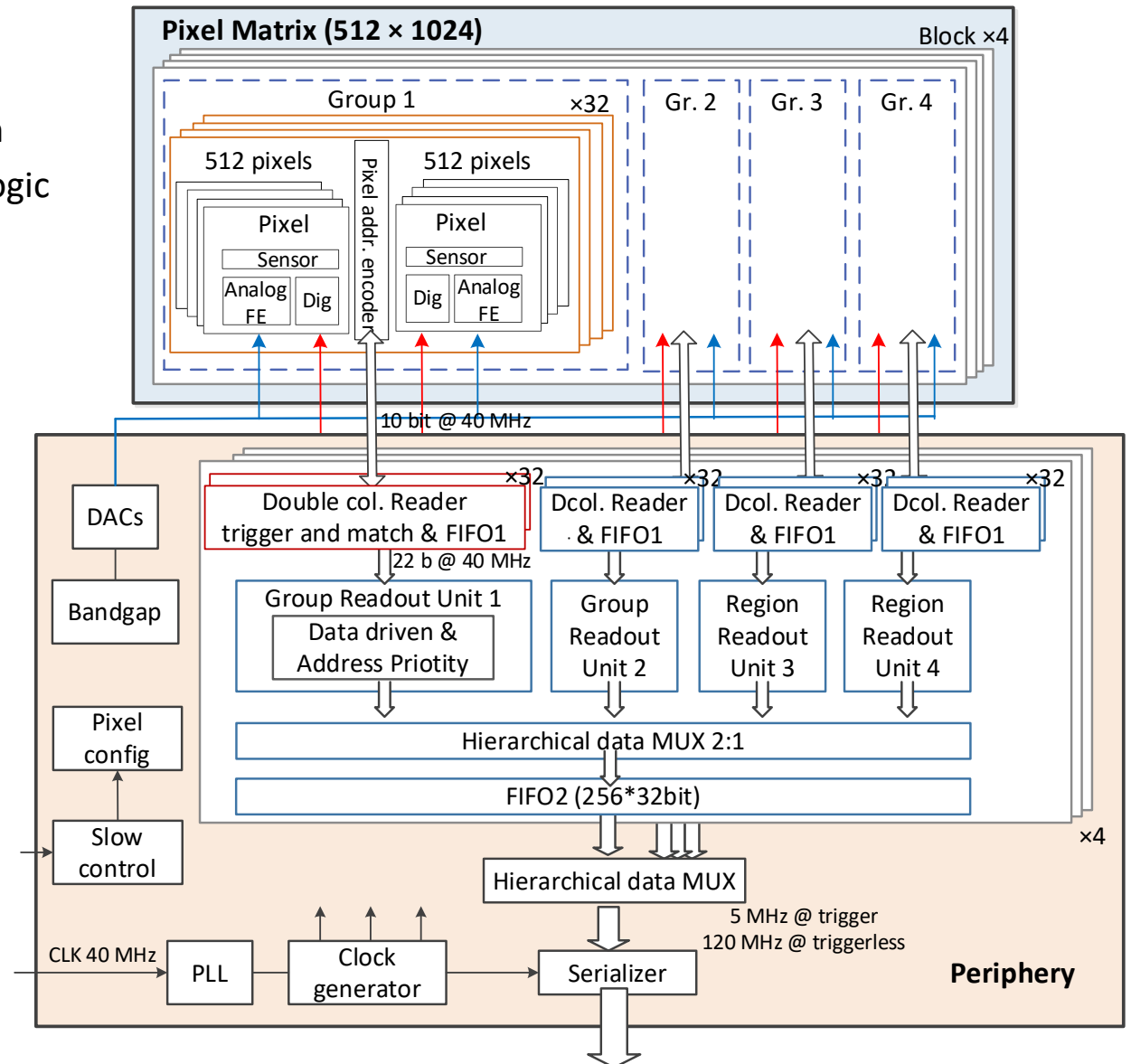
# Thank you for your attention!



中國科學院高能物理研究所  
*Institute of High Energy Physics*  
*Chinese Academy of Sciences*

# TaichuPix architecture

- Pixel  $25\ \mu\text{m} \times 25\ \mu\text{m}$ 
  - Continuously active front-end, in-pixel discrimination
  - Fast-readout digital, with masking & testing config. logic
- Column-drain readout for pixel matrix
  - Priority based data-driven readout
  - Readout time: 50 ns for each pixel
- 2-level FIFO architecture
  - L1 FIFO: de-randomize the injecting charge
  - L2 FIFO: match the in/out data rate
  - between core and interface
- Trigger-less & Trigger mode compatible
  - Trigger-less: 3.84 Gbps data interface
  - Trigger: data coincidence by time stamp  
only matched event will be readout
- Features standalone operation
  - On-chip bias generation, LDO, slow control, etc

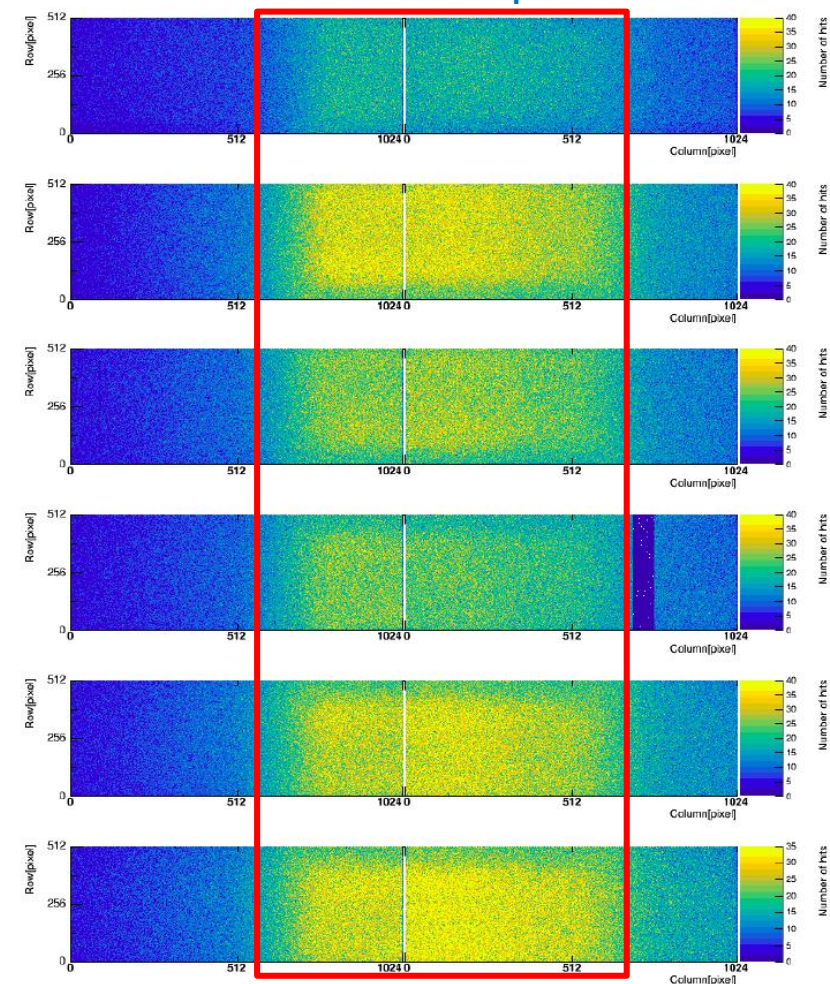
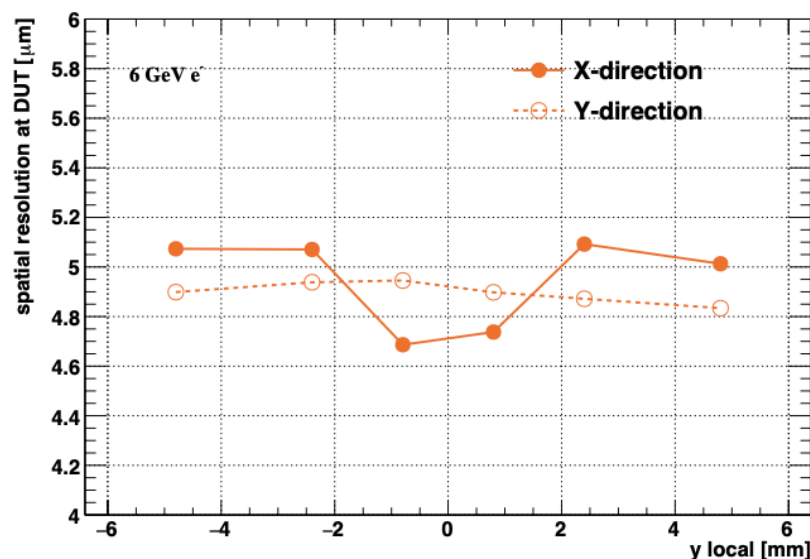
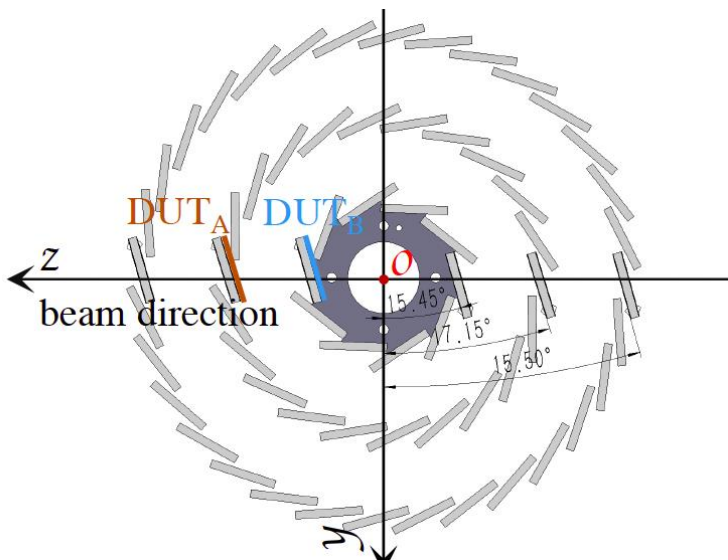


# R&D efforts and results: vertex detector prototype beam test

Spatial resolution  $\sim 5 \mu\text{m}$  Efficiency  $>99\%$

Hit maps of multiple layers of vertex detector

Beam spot



	Status	CEPC Final goal
Spatial resolution	4.9 $\mu\text{m}$	3-5 $\mu\text{m}$



# Background estimation

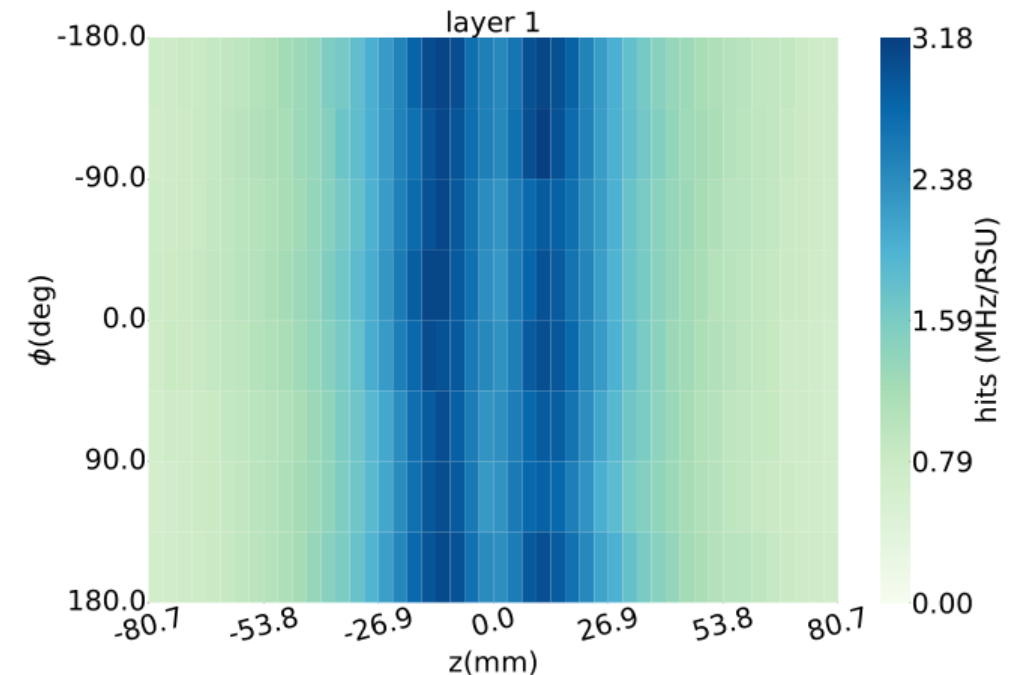
## ■ Background rate are simulated

- The data rate at low-lumi Z pole is about ~Gbps level in b-layer

### Background rate for Higgs and low-lumi Z runs

Layer	Ave. Hit Rate (MHz/cm <sup>2</sup> )	Max. Hit Rate (MHz/cm <sup>2</sup> )	Ave. Data Rate (Mbps/cm <sup>2</sup> )	Max. Data Rate (Mbps/cm <sup>2</sup> )
Higgs mode: Bunch Spacing: 277 ns, 63% Gap				
1	6.2	12	760	1500
2	0.84	1.6	87	160
3	0.17	0.36	19	38
4	0.067	0.16	8.4	19
5	0.017	0.037	2.1	4.2
6	0.013	0.026	1.6	3.7
Low-luminosity Z mode: Bunch Spacing: 69 ns, 17% Gap				
1	15	39	2700	8100
2	1.7	2.6	240	400
3	0.72	1.2	110	240
4	0.43	0.94	70	210
5	0.10	0.19	14	31
6	0.078	0.15	11	23

### Hit rate map for 1<sup>st</sup> layer @ low-lumi Z run

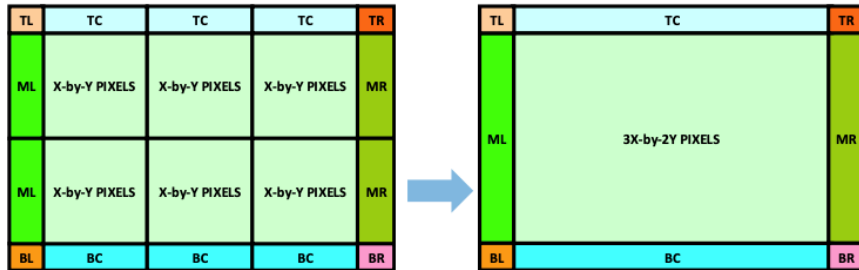


# R&D efforts and results:

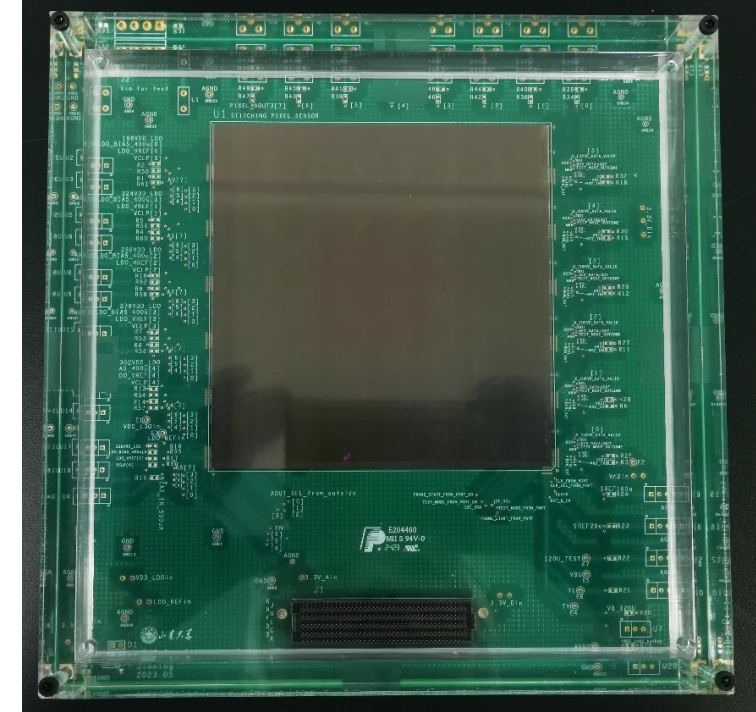
## R&D for curved MAPS

### ■ Stitching chip design (by ShanDong U.)

- 350 nm CIS technology Xfabs
- Wafer level size after stitching  $\sim 11 \times 11 \text{ cm}^2$
- reticle size  $\sim 2 \times 2 \text{ cm}^2$
- 2D stitching
- Engineering run, chip under testing



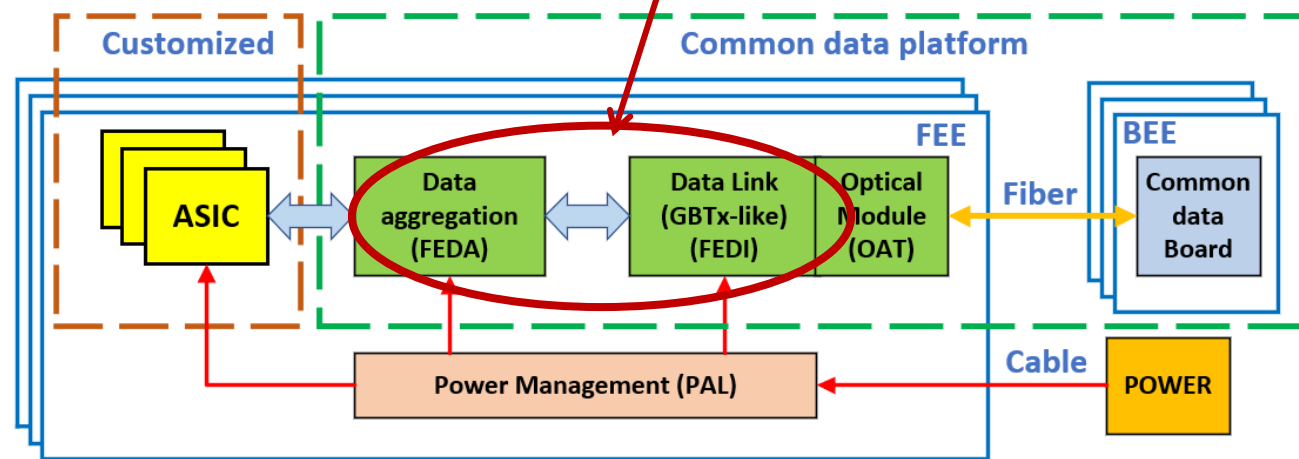
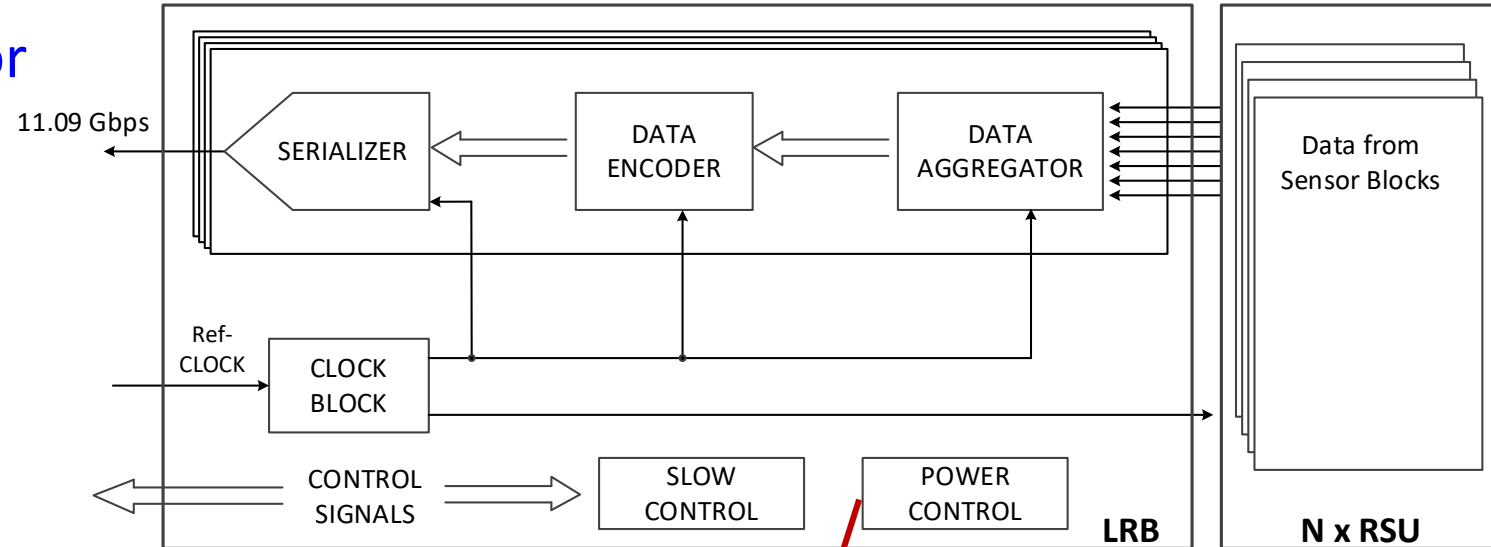
Stitching chip :  $11 \times 11 \text{ cm}^2$



Key technology	Status	CEPC Final goal
Stitching	11*11cm stitched chip with Xfab 350 nm CIS	65 nm CIS stitched sensor

# Data Transmission Structure

## ■ LRB in stitched sensor



Common data transmission ASICS